## Lecture 9 Noise in Switched-Capacitor Circuits

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#### **Lecture Plan**

Date	Lecture (Wednesday 2-4pm)		Reference	Homework		
2020-01-07	1	MOD1 & MOD2	PST 2, 3, A	1: Matlab MOD1&2		
2020-01-14	2	MOD <i>N</i> + ΔΣ Toolbox	PST 4, B	2: ΔΣ Toolbox		
2020-01-21	3	SC Circuits	R 12, CCJM 14			
2020-01-28	4	Comparator & Flash ADC	CCJM 10	3: Comparator		
2020-02-04	5	Example Design 1	PST 7, CCJM 14			
2020-02-11	6	Example Design 2	CCJM 18	4. SC MOD2		
2020-02-18		Reading Week / ISSC	4: 5C WOD2			
2020-02-25	7	Amplifier Design 1				
2020-03-03	8	Amplifier Design 2		Project		
2020-03-10	9	Noise in SC Circuits				
2020-03-17	10	Nyquist-Rate ADCs	CCJM 15, 17			
2020-03-24	11	Mismatch & MM-Shaping	PST 6			
2020-03-31	12	Continuous-Time $\Delta\Sigma$	PST 8			
2020-04-07		Exam				
2020-04-21	Project Presentation (Project Report Due at start of class)					

## **Circuit of the Day: Constant-G<sub>M</sub> Biasing**

- How do we bias transistors so that the transconductance does not depend on:
  - Temperature
  - Process
  - **Supply Voltage**
- Make it dependent on a bias resistor R<sub>B</sub>

$${m g}_m \propto {m 1\over {m R}_{\scriptscriptstyle B}}$$



### What you will learn...

- How to analyze noise in switched-capacitor circuits
- Significance of switch noise vs. OTA noise Power efficient solution

Impact of OTA architecture

• Design example for  $\Delta\Sigma$  modulator

#### Review

 Previous analysis of kT/C noise (ignoring OTA/opamp noise)

> Phase 1: kT/C<sub>1</sub> noise (on each side) Phase 2: kT/C<sub>1</sub> added to previous noise (on each side) Total Noise (input referred): 2kT/C<sub>1</sub> Differentially: 4kT/C<sub>1</sub>



#### Review

#### SNR (differential)

Total noise power: 4kT/C<sub>1</sub> Signal power: (2V)<sup>2</sup>/2 SNR: V<sup>2</sup>C<sub>1</sub>/2kT

#### SNR (single-ended)

Total noise power:  $2kT/C_1$  (sampling capacitor  $C_1$ ) Signal power: V<sup>2</sup>/2 (signal from -V to V) SNR: V<sup>2</sup>C<sub>1</sub>/4kT

• Two noise sources  $V_{C1}$  and  $V_{OUT}$ 

V<sub>C1</sub>: Represents input-referred sampled noise on input switching transistors + OTA

V<sub>OUT</sub>: Represents output-referred (non-sampled) noise from OTA



### **Thermal Noise in OTAs**

#### • Single-Ended Example

Noise current from each transistor is  $\overline{I_n^2} = 4kT\gamma g_m$ Assume  $\gamma = 2/3$ 



## **Thermal Noise in OTAs**

#### Single-Ended Example

Thermal noise in single-ended OTA

Assuming paths match, tail current source M<sub>5</sub> does not contribute noise to output

**PSD** of noise voltage in  $M_1$  (and  $M_2$ ):

 $\frac{8}{3}\frac{kT}{g_{m1}}$ 

PSD of noise voltage in M<sub>3</sub> (and M<sub>4</sub>):  $\frac{8}{3} \frac{kTg_{m3}}{g_{m1}^2}$ 

Total input referred noise from M<sub>1</sub> - M<sub>4</sub>

$$S_{n,eq} = \frac{16}{3} \frac{kT}{g_{m1}} \left( 1 + \frac{g_{m3}}{g_{m1}} \right) = \frac{16}{3} \frac{kT}{g_{m1}} n_M$$

Noise multiplier  $n_M$  depends on architecture

• Analyze output noise in single-stage OTA Use capacitive feedback in the amplification / integration phase of a switched-capacitor circuit





Transfer function of closed loop OTA

$$H(s) = \frac{V_{OUT}}{V_{n,eq}} = \frac{G}{1 + s/\omega_o}$$

where the DC Gain and 1st-pole frequency are

$$\mathbf{G} \approx \frac{1}{\beta} = \mathbf{1} + \mathbf{C}_1 / \mathbf{C}_2 \qquad \qquad \boldsymbol{\omega}_o = \frac{\beta \mathbf{g}_{m1}}{\mathbf{C}_o}$$

Load capacitance  $C_0$  depends on the type of OTA – for a single-stage, it is  $C_L+C_1C_2/(C_1+C_2)$ , while for a twostage, it is the compensation capacitor  $C_c$ 

Integrate total noise at output

$$\overline{V_{OUT}^2} = \int_0^\infty S_{n,eq}(f) |H(j2\pi f)|^2 df$$
$$= \frac{16}{3} \frac{kT}{g_{m1}} n_M \frac{\omega_o}{4} G^2$$
$$= \frac{4kT}{3\beta C_0} n_M$$
Minimum output noise for  $\beta$ =1 is  $\frac{4kT}{3C_0} n_M$ 

Not a function of  $g_{m1}$  since bandwidth is proportional to  $g_{m1}$  while PSD is inversely proportional to  $g_{m1}$ 

• Graphically...



Noise is effectively filtered by equivalent brick wall response with cut-off frequency  $\pi f_o/2$  (or  $\omega_o/4$  or  $1/4\tau$ ) Total noise at V<sub>OUT</sub> is the integral of the noise within the brick wall filter (area is simply  $\pi f_o/2 \ge G^2$ )

## **Sampled Thermal Noise**

#### What happens to noise once it gets sampled?

Total noise power is the same

Noise is aliased – folded back from higher frequencies to lower frequencies

**PSD** of the noise increases significantly



## **Sampled Thermal Noise**



Same total area, but PSD is larger from 0 to f<sub>s</sub>/2

$$S_{Vo,S}(f) = \frac{\overline{V_{OUT}^2}}{f_S/2} = \frac{G^2 S_{n,eq}}{4\tau f_S/2} = \frac{4kT}{3\beta C_0} n_M \frac{1}{f_S/2}$$
  
Low frequency PSD  $G^2 S_{n,eq}$  is increased by  $\frac{\pi f_0/2}{f_S/2} = \frac{\pi f_0}{f_S}$ 

## **Sampled Thermal Noise**

1/f<sub>0</sub> is the settling time of the system, while 1/2f<sub>S</sub> is the settling period for a two-phase clock

$$e^{-\frac{1/2f_s}{\tau}} < 2^{-(N+1)}$$
  
 $\frac{\pi f_0}{f_s} > (N+1) \ln 2$ 

PSD is increased by at least  $(N+1)\ln 2$ 

If N = 10 bits, PSD is increased by 7.6, or 8.8dB

 This is an inherent disadvantage of sampleddata systems (compared to continuous-time)
 But noise is reduced by oversampling ratio after digital

filtering

Using the parasitic-insensitive SC integrator



- Two phases to consider
  - 1) Sampling Phase

Includes noise from both  $\phi_1$  switches

2) Integrating Phase

Includes noise from both  $\phi_2$  switches and OTA

• Phase 1: Sampling



Noise PSD from two switches:  $S_{Ron}(f) = 8kTR_{ON}$ Time constant of R-C filter:  $\tau = 2R_{ON}C_1$ Noise voltage across  $C_1$ 

$$\overline{V_{C1,sw1}^2} = \int_0^\infty S_{Ron}(f) \left|\frac{1}{1+s\tau}\right|^2 df$$

#### • Phase 1: Sampling

Integrated across entire spectrum, total noise power in  $C_1$  is

$$\overline{V_{C1,sw1}^2} = \frac{8 \, kTR_{ON}}{4\tau} = \frac{kT}{C_1}$$

Independent of  $R_{ON}$  (PSD is proportional to  $R_{ON}$ , bandwidth is inversely proportional to  $R_{ON}$ ) After sampling, charge is trapped in  $C_1$ 



Two noise sources: switches and OTA
 Noise PSD from two switches: S<sub>Ron</sub>(f) = 8kTR<sub>ON</sub>

Noise PSD from OTA: 
$$S_{vn,eq}(f) = \frac{16}{3} \frac{kT}{g_{m1}} n_M$$

Noise power across C<sub>1</sub> charges to  $2\overline{V_{Ron}^2} + \overline{V_{n,eq}^2}$ 

• What is the time-constant?



Analysis shows that  $Z_{IN} = \frac{1/sC_2 + R_L}{1 + g_{m1}R_L}$ For large R<sub>L</sub>, assume that  $Z_{IN} \approx \frac{1}{g_{m1}}$ 

Resulting time constant  $\tau = (2R_{ON} + 1/g_{m1})C_1$ 

 Total noise power with both switches and OTA on integrating phase

$$\overline{V_{C1,op}^2} = \frac{S_{vn,eq}(f)}{4\tau} \qquad \overline{V_{C1,sw2}^2} = \frac{S_{Ron}(f)}{4\tau}$$
$$= \frac{16kT}{3g_{m1}} \frac{n_M}{4(2R_{oN} + 1/g_{m1})C_1} \qquad = \frac{8kTR_{oN}}{4(2R_{oN} + 1/g_{m1})C_1}$$
$$= \frac{4kT}{C_1} \frac{n_M}{(1+x)} \qquad = \frac{kT}{C_1} \frac{x}{(1+x)}$$

Introduced extra parameter  $x = 2R_{oN}g_{m1}$ 



#### Total noise power on C1 from both phases

$$\overline{V_{C1,diff}^2} = \overline{V_{C1,op}^2} + \overline{V_{C1,sw1}^2} + \overline{V_{C1,sw2}^2}$$
$$= \frac{4kT}{3C_1} \frac{n_M}{(1+x)} + \frac{kT}{C_1} \frac{x}{(1+x)} + \frac{kT}{C_1}$$
$$= \frac{kT}{C_1} \left(\frac{4n_M/3 + 1 + 2x}{1+x}\right)$$

Lowest possible noise achieved if  $X \rightarrow \infty$ 

In this case, 
$$\overline{V_{C1}^2} = \frac{2kT}{C_1}$$

What was assumed to be the total noise was actually the least possible noise!

#### **Noise Contributions**

 Percentage noise contribution from switches and OTA (assume n<sub>M</sub>=1.5)



#### **Noise Contributions**

- When R<sub>ON</sub> >> 1/g<sub>m1</sub> (x >> 1)...
  Switch dominates both bandwidth and noise Total noise power is minimized
- When R<sub>ON</sub> << 1/g<sub>m1</sub> (x << 1)...

OTA dominates both bandwidth and noise Power-efficient solution

Minimize  $g_{m1}$  (and power) for a given settling time and noise

$$g_{m1} = \frac{kT}{\tau \overline{V_{C1}^2}} \left(\frac{4}{3}n_M + 1 + 2x\right)$$

Minimized for x=0

### **Amplifier Noise**

How much larger can the noise get?
 Depends on n<sub>M</sub>... (table excludes cascode noise)

Architecture	Relative V <sub>EFF</sub> 's	n <sub>M</sub>	Maximum Noise (x=0)	+dB
Telescopic/ Diff.Pair	V <sub>EFF,1</sub> =V <sub>EFF,n</sub> /2	1.5	3⋅kT/C <sub>1</sub>	1.76
Telescopic/ Diff.Pair	V <sub>EFF,1</sub> =V <sub>EFF,n</sub>	2	3.67 <sup>.</sup> kT/C <sub>1</sub>	2.63
Folded Cascode	V <sub>EFF,1</sub> =V <sub>EFF,n</sub> /2	2.5	4.33 <sup>.</sup> kT/C <sub>1</sub>	3.36
Folded Cascode	V <sub>EFF,1</sub> =V <sub>EFF,n</sub>	4	6.33 <sup>.</sup> kT/C <sub>1</sub>	5.01

#### **Separate Input Capacitors**

Using separate input caps increases noise

Each additional input capacitor adds to the total noise Separate caps help reduce signal dependent disturbances in the DAC reference voltages



#### **Differential vs. Single-Ended**

Single-Ended Noise

$$\overline{V_{C1,se}^2} = \frac{kT}{C_1} \left( \frac{4n_M/3 + 1 + 2x}{1 + x} \right)$$

Differential Noise

$$\overline{V_{C1,diff}^2} = \overline{V_{C1,op}^2} + \overline{V_{C1,sw1}^2} + \overline{V_{C1,sw2}^2}$$
$$= \frac{4kT}{3C_1} \frac{n_M}{(1+x)} + \frac{2kT}{C_1} \frac{x}{(1+x)} + \frac{2kT}{C_1}$$
$$= \frac{kT}{C_1} \left(\frac{4n_M/3 + 2 + 4x}{1+x}\right)$$

Relative Noise (for n<sub>f</sub>=1.5, x=0)

$$\frac{\overline{V_{C1,diff}^2}}{\overline{V_{C1,se}^2}} = \frac{4n_M/3 + 2 + 4x}{4n_M/3 + 1 + 2x} = \frac{4}{3}$$

## **Differential vs. Single-Ended**

- All previous calculations assumed single-ended operation
  - For same settling time,  $g_{m1,2}$  is the same, resulting in the same total power [0dB]
  - Differential input signal is twice as large [gain 6dB]
  - Differential operation has twice as many caps and therefore twice as much capacitor noise (assume same size per side  $C_1$  and  $C_2$ ) [lose ~1.2dB for  $n_M$ =1.5, x=0... less for larger  $n_M$ ]
- Net Improvement: ~4.8dB

What is the total output-referred noise in an integrator?

Assume an integrator transfer function



#### Total output-referred noise PSD

 $S_{INT}(f) = S_{C1}(f)|H(z)|^2 + S_{OUT}(f)$ 

where 
$$\overline{V_{OUT}^2} = \frac{4kT}{3\beta C_0} n_M$$
  
and  $\overline{V_{C1}^2} = \frac{kT}{C_1} \left(\frac{4n_M/3 + 1 + 2x}{1 + x}\right)$ 

Since all noise sources are sampled, white PSDs

$$S_x = \frac{\overline{V_x^2}}{f_S/2}$$

To find output-referred noise for a given OSR in a  $\Delta\Sigma$ modulator:  $F_{S/(2 \cdot OSR)}$  $\overline{V_{INT}^2} = \int S_{INT}(f) df$ 

- How do we find the total input-referred noise in a  $\Delta\Sigma$  modulator?
  - **1)** Find all thermal noise sources
  - 2) Find PSDs of the thermal noise sources
  - 3) Find transfer functions from each noise source to the output
  - 4) Using the transfer functions, integrate all PSDs from DC to the signal band edge f<sub>s</sub>/2·OSR
  - 5) Sum the noise powers to determine the total output thermal noise
  - 6) Input noise = output noise (assuming STF is ~1 in the signal band)

#### • Example

 $f_s = 100MHz$ , T = 10ns, OSR = 32 SNR = 80dB (13-bit resolution) Input Signal Power =  $0.25V^2$  (-6dB from  $1V^2$ ) Noise Budget: 75% thermal noise Total input referred thermal noise:

$$\overline{V_{TH}^2} = 0.75 \cdot 10^{(-6-SNR)/10} \cdot 1V^2 = (43.4\mu V)^2$$



#### 1) Find all thermal noise sources



$$\overline{V_{n3}^2} = \frac{2kT}{C_{f1}} \left( 1 + \frac{C_{f2}}{C_{f1}} + \frac{C_{f3}}{C_{f1}} \right) = \frac{2kT}{C_{f1}} \left( 1 + 2 + 1 \right)$$

#### 2) Find PSDs of the thermal noise sources

For each of the mean square voltage sources,

$$\mathbf{S}_{\mathbf{x}} = \frac{\overline{V_{\mathbf{x}}^2}}{f_{\mathbf{S}} / 2}$$

3) Find transfer functions from each noise source to the output

Assume ideal integrators  $H_{A}(z) = H_{B}(z) = \frac{z^{-1}}{1 - z^{-1}}$  STF(z) = 1 $NTF(z) = (1 - z^{-1})^{2} = \frac{1}{1 + 2H(z) + H(z)^{2}}$ 

## 3) Find transfer functions from each noise source to the output

From input of  $H_A(z)$  to output...

$$NTF_{i1}(z) = \left(2H(z) + H(z)^{2}\right)NTF(z)$$
$$= \frac{2H(z) + H(z)^{2}}{1 + 2H(z) + H(z)^{2}} = 2z^{-1} - z^{-2}$$

From output of  $H_A(z)$  to output...

$$NTF_{o1}(z) = (2 + H(z)) NTF(z)$$
$$= \frac{2 + H(z)}{1 + 2H(z) + H(z)^{2}} = (1 - z^{-1})(2 - z^{-1})$$

## 3) Find transfer functions from each noise source to the output

From input of  $H_B(z)$  to output...

$$NTF_{i2}(z) = H(z)NTF(z)$$
$$= \frac{H(z)}{1+2H(z)+H(z)^{2}} = z^{-1}(1-z^{-1})$$

From output of  $H_B(z)$  to output (equal to transfer function at input of summer to output)...

$$NTF_{o2}(z) = NTF(z) = (1 - z^{-1})^2$$



# 3) Find transfer functions from each noise source to the output

Most significant is NTF<sub>i1</sub>



4) Using the transfer functions, integrate all PSDs from DC to the signal band edge f<sub>s</sub>/2·OSR

Use MATLAB/Maple to solve the integrals...

$$\overline{V_{i1}^2} = \frac{\overline{V_{ni1}^2}}{f_s / 2} \int_{0}^{f_s / (2 \cdot OSR)} |NTF_{i1}(f)|^2 df$$
$$= \frac{\overline{V_{ni1}^2}}{f_s / 2} \left[ \frac{5f_s}{2 \cdot OSR} - \frac{2f_s}{\pi} \sin\left(\frac{\pi}{OSR}\right) \right]$$

$$\overline{V_{01}^2} = \frac{\overline{V_{no1}^2}}{f_s/2} \int_0^{f_s/(2 \cdot OSR)} |NTF_{o1}(f)|^2 df$$
$$= \frac{\overline{V_{no1}^2}}{f_s/2} \left[ \frac{7f_s}{OSR} + \frac{2f_s}{\pi} \sin\left(\frac{\pi}{OSR}\right) \cos\left(\frac{\pi}{OSR}\right) - \frac{9f_s}{\pi} \sin\left(\frac{\pi}{OSR}\right) \right]$$

4) Using the transfer functions, integrate all PSDs from DC to the signal band edge f<sub>s</sub>/2·OSR

$$\overline{V_{i2}^2} = \frac{\overline{V_{ni2}^2}}{f_s / 2} \left[ \frac{f_s}{OSR} - \frac{f_s}{\pi} \sin\left(\frac{\pi}{OSR}\right) \right]$$

$$\overline{V_{02}^2} = \frac{\overline{V_{n02}^2} + \overline{V_{n3}^2}}{f_s / 2} \left[ \frac{3f_s}{OSR} + \frac{f_s}{\pi} \sin\left(\frac{\pi}{OSR}\right) \cos\left(\frac{\pi}{OSR}\right) - \frac{4f_s}{\pi} \sin\left(\frac{\pi}{OSR}\right) \right]$$

(Some simplifications can be made for large OSR)

5) Sum the noise powers to determine the total output thermal noise

Assume  $x_A = x_B = 0.1$  and  $n_{M,A} = n_{M,B} = 1.5$ 

$$\overline{V_{TH}^{2}} \approx \frac{2.9 \, kT}{C_{1A}} \frac{1}{OSR} + \frac{2 \, kT}{\beta_{A} C_{OA}} \frac{\pi^{2}}{3 OSR^{3}} + \frac{2.9 \, kT}{C_{1B}} \frac{\pi^{2}}{3 OSR^{3}} + \frac{4 \, \frac{\pi^{2}}{3 OSR^{3}}}{\frac{\pi^{4}}{\beta_{B} C_{OB}}} + \frac{2 \, kT}{\beta_{B} C_{OB}} \frac{\pi^{4}}{5 OSR^{5}} + \frac{8 \, kT}{C_{f1}} \frac{\pi^{4}}{5 OSR^{5}} + \frac{1}{2 \, N} \frac{\pi^{4}}{3 \, N} +$$

With an OSR of 32, first term is most significant (assume  $\beta_A = \beta_B = 1/3$ )

$$\overline{V_{TH}^2} \approx 9.1 \times 10^{-2} \frac{kT}{C_{1A}} + 6.0 \times 10^{-4} \frac{kT}{C_{OA}} + 2.9 \times 10^{-4} \frac{kT}{C_{1B}} + \dots$$

6) Input noise = output noise (assuming STF is ~1 in the signal band)

$$\overline{V_{TH}^2} \approx 9.1 \times 10^{-2} \frac{kT}{C_{1A}} = (43.4 \,\mu\text{V})^2$$
$$\Rightarrow C_{1A} = 200\text{fF}$$

Assuming other capacitors are smaller than  $C_{1A}$ , then subsequent terms are insignificant and the approximation is valid

If lower oversampling ratios are used, other terms may become more significant in the calculation

## Noise in a Pipeline ADC

• Similar procedure to  $\Delta\Sigma$  modulator, except transfer functions are much easier to compute

#### Differences...

Input refer all noise sources

Gain from each stage to the input is a scalar

Noise from later stages will be more significant since typical stage gains are as low as 2

Sample-and-Hold adds extra noise which is input referred with a gain of 1

Entire noise power is added since the signal band is from 0 to  $f_s/2$  (OSR=1)

### Noise in a Pipeline ADC

#### • Example

If each stage has a gain  $G_1, G_2, \dots G_N$ 

$$\overline{N_i^2} = \overline{V_{ni1}^2} + \frac{\overline{V_{no1}^2} + \overline{V_{ni2}^2}}{G_1^2} + \frac{\overline{V_{no2}^2} + \overline{V_{ni3}^2}}{G_1^2 G_2^2} + \dots + \frac{\overline{V_{noN}^2}}{G_1^2 G_2^2 \dots G_N^2}$$

S/H stage noise will add directly to  $V_{ni1}$ 



## **Circuit of the Day: Constant-G<sub>M</sub> Biasing**



## **Further Reading**

- Appendix C of Understanding Delta-Sigma Data Converters, Schreier and Temes (1<sup>st</sup> edition)
- Schreier et al., *Design-Oriented Estimation of Thermal* Noise in Switched-Capacitor Circuits, TCAS-I, Nov. 2005